

SLOVENSKI STANDARD SIST ISO 13655:2018

01-februar-2018

Nadomešča: SIST ISO 13655:2010

Grafična tehnologija - Spektrometrija in kolorimetrični izračuni za grafične upodobitve

Graphic technology - Spectral measurement and colorimetric computation for graphic arts images

iTeh STANDARD PREVIEW

(standards.iteh.ai)

Technologie graphique - Mesurage spectral et calcul colorimétrique relatifs aux images dans les arts graphiques <u>SIST ISO 13655:2018</u> https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-

21183c0cb3d8/sist-iso-13655-2018

21183C0C03d8/SISt-ISO-13055-2018

Ta slovenski standard je istoveten z: ISO 13655:2017

ICS:

17.180.20	Barve in merjenje svetlobe	Colours and measurement of light
37.100.01	Grafična tehnologija na splošno	Graphic technology in general

SIST ISO 13655:2018

en,fr



iTeh STANDARD PREVIEW (standards.iteh.ai)

SIST ISO 13655:2018 https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-21183c0cb3d8/sist-iso-13655-2018

SIST ISO 13655:2018

INTERNATIONAL STANDARD

ISO 13655

Third edition 2017-07

Graphic technology — Spectral measurement and colorimetric computation for graphic arts images

Technologie graphique — Mesurage spectral et calcul colorimétrique relatifs aux images dans les arts graphiques

iTeh STANDARD PREVIEW (standards.iteh.ai)

SIST ISO 13655:2018 https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-21183c0cb3d8/sist-iso-13655-2018



Reference number ISO 13655:2017(E)

iTeh STANDARD PREVIEW (standards.iteh.ai)

SIST ISO 13655:2018 https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-21183c0cb3d8/sist-iso-13655-2018



© ISO 2017, Published in Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized otherwise in any form or by any means, electronic or mechanical, including photocopying, or posting on the internet or an intranet, without prior written permission. Permission can be requested from either ISO at the address below or ISO's member body in the country of the requester.

ISO copyright office Ch. de Blandonnet 8 • CP 401 CH-1214 Vernier, Geneva, Switzerland Tel. +41 22 749 01 11 Fax +41 22 749 09 47 copyright@iso.org www.iso.org

Contents

Page

Forev	vord		v
Intro	ductio	n	vi
1	Scop	e	
2	Normative references		
3	Tern	ns and definitions	1
4	Snectral measurement requirements		
	4.1 4.2	Instrument standardization and adjustment Reflectance factor measurement 4.2.1 Wavelength range, wavelength interval and bandwidth 4.2.2 Illumination requirements and measurement conditions 4.2.3 Sample backing material	
	4.3	 4.2.4 Measurement geometry 4.2.5 Data reporting Transmittance factor measurement 4.3.1 Wavelength range, wavelength interval and bandwidth 4.3.2 Measurement geometry 4.3.3 Illumination requirements and measurement conditions 4.3.4 Resolution and data reporting 	7 7 8 8 8 8 8 8 8 8
	4.4	 Self-luminous displays (spectral radiance) measurement. 4.4.1 Wavelength range, wavelength interval and bandwidth. 4.4.2 Measurement geometry. 4.4.3 Polarization tangenetry. 4.4.4 Resolution and data reporting. 	9 9 9 9 10
5	Colo:	rimetric computation requirements55:2018	
	5.1	 5.1.1 General	10 10 11 11 11 11 11
	5.3	 CIE 1976 (<i>L*a*b*</i>) colour space; CIELAB colour space	13 13 13 13 14 14
6	Measurement data reporting requirements		
	6.1 6.2 6.3	Required information Recommended information Electronic data reporting	
Anne	x A (no	ormative) Sample backing	
Anne	x B (in	formative) Geometry	
Anne	x C (in	formative) Improving inter-instrument agreement	
Anne	x D (in	formative) Certified reference materials (CRMs)	
Anne	x E (in	formative) Procedures for widening the bandwidth	
Anne	x F (in	formative) Fluorescent specimens	30
Anne	x G (no	prmative) Test method for UV-cut conformance	
Anne	x H (in	formative) Special cases: Use of polarization	

SIST ISO 13655:2018

ISO 13655:2017(E)

Annex I (informative) Example computations for converting spectral measurements to	25
tristimulus values	
Annex J (normative) Computation of the CIELAB total colour difference (ΔE*ab)	
Annex K (normative) Computation of the CIEDE2000 total colour difference (ΔE_{00})	
Annex L (informative) Impact of measurement band pass on spectral quantities	
Bibliography	

iTeh STANDARD PREVIEW (standards.iteh.ai)

SIST ISO 13655:2018 https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-21183c0cb3d8/sist-iso-13655-2018

Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation on the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see the following URL: www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 130, *Graphic technology*, in collaboration with Technical Committee ISO/TC 42, *Photography*,5:2018 https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-

This third edition cancels and replaces the second edition (ISO 13655:2009), which has been technically revised to:

- clarify the requirements of measurement mode M1;
- restrict the use of unnecessarily wide bandpass and sampling intervals;
- provide more realistic specification for the optical properties of a white backing material;
- restrict the adjustment method of predicting the fluorescent reflectance factor to UV activated substrates.

Introduction

There are many choices allowed when making spectral measurements and performing colorimetric computations. The specific choices made can result in different numerical values for the same property for the same sample. Thus, it might not be possible to make valid comparisons unless the data being compared are all based on the same set of measurement and computational choices. The purpose of this document is to specify a limited number of such choices for the measurement and computation of the colorimetric characteristics of graphic arts images and specimens, such as test charts, to allow valid and comparable data to be obtained. While this document references ISO 3664, the International Standard established for viewing conditions in graphic arts and photography, it is not expected that measured colorimetric data will provide an absolute correlation with visual colour appearance.

When the prior revision of this document was started, it was observed that almost all graphic arts specimens exhibited fluorescence. In most cases, this was due to optical brightening agents (OBA) contained in the paper substrates. In rare cases, the printing inks were fluorescent. According to the recommendations of the 1996 version of this document, this would have meant that the source used for the measurements (i.e. the spectral power distribution of the specimen illumination) was required to closely match CIE illuminant D50. Yet when the 2009 revision was started, not a single colour-measuring instrument sold for the graphic arts market provided an illumination system that closely matched CIE illuminant D50. Instead, most instruments used incandescent lamps for light sources. The spectral power distributions of such lamps have varying amounts of UV content. The variation in UV content between instruments could easily amount to a colour difference of 5 Δ b* when measuring substrates with a high level of optical brightening agents. Consequently, the measurement results for unprinted paper substrates and lighter colours differed appreciably between different instrument models. For a thorough study of fluorescence effects, see CIE Publication 163.

It had also been observed that graphic **arts viewing booths vary with r**espect to UV content, even those that comply with the 1996 version of ISO 3664. The practical result was that specimens that have nearly identical measured colorimetric properties, at **times will not visually** match when viewed in the viewing booth, and vice versa. Only part of such discrepancies can be attributed to fluorescence. There can also be metameric effects due to "non-standard" observers and to instrument wavelength errors, in addition to deviations in the measurement source away from CIE D50. Despite these other potential influences, it was deemed important to provide measurement solutions that would minimize the systematic errors introduced by the interaction of paper fluorescence and variations in the spectral power distribution of the sample illumination. Methods for the correction of instrument errors and procedures for reliable visual evaluation of colour images are outside of the scope of this document.

In the 2009 revision, four measurement choices were defined for reflective measurements. Measurement condition M0 requires the source illumination to closely match that of illuminant A; this provides consistency with existing instrumentation and ISO 5-3. Measurement condition M1 requires the colorimetry of the specimen illumination to closely match CIE illuminant D50. Measurement condition M2 only requires that the spectral power distribution of the specimen illumination be provided in the wavelength range from 400 nm to at least 700 nm and have no substantial radiation power in the wavelength range below 400 nm (often referred to as "UVCut"). Measurement condition M3 has the same sample illumination requirements as M2 and includes a linear polarizer in the influx and efflux portions of the optical path with their principal axes of polarization in the orthogonal or "crossed" orientation. For specimens in which the fluorescence is primarily that of a UV activated blue emission, it is possible to use the method of a virtual fluorescent standard reported by Imura of Konica Minolta^{[24][25]} to determine the total radiance factors for M0, M1 and M2 conditions. In this revision, Annex A has been revised providing a slightly narrower and more realistic set of spectral tolerances on the white backing materials. The properties of the white backing material are critical to reproducibility of readings of packaging printing on clear or translucent films.

Finally, as the CIE has been recommending the use of 5 nm intervals for practical tristimulus integration since the second revision of CIE Publication 15 and as graphic images can be composed of colour stimulus functions with very narrow transitions from the low values to the high values, this revision recommends that tristimulus values be based on spectral data collected with a 5 nm interval and a 5 nm bandpass. Since many of the instruments now in use in the field are equipped with 10 nm

intervals and 10 nm bandpass spectrometers, such readings are allowed with the recommendation that tristimulus calculations be preceded by applying bandpass correction to the spectral data as specified in ASTM E2729. The use of instruments with wider sampling intervals and bandpass has been deprecated with the exception of the use of such non-standard instruments to monitor the state of previously characterized materials or objects.

The requirements of this document are focused on colorimetric measurement equipment intended for use in the graphic arts environment. Helpful information on issues such as substrate backing materials, reporting, standardization, standard and improved colour difference metrics, fluorescence and ways to improve the inter-instrument agreement are included. These will be useful to technical advisors of graphic arts associations, specialized graphic arts research institutes, and practitioners with an interest in the basics of measurement and process control.

iTeh STANDARD PREVIEW (standards.iteh.ai)

SIST ISO 13655:2018 https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-21183c0cb3d8/sist-iso-13655-2018



iTeh STANDARD PREVIEW (standards.iteh.ai)

<u>SIST ISO 13655:2018</u> https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-21183c0cb3d8/sist-iso-13655-2018

Graphic technology — Spectral measurement and colorimetric computation for graphic arts images

1 Scope

This document specifies procedures for the measurements and colorimetric computations appropriate to objects that reflect, transmit and emit light, such as flat-panel displays. It also specifies procedures for computation of colorimetric parameters for graphic arts images. Graphic arts include, but are not limited to, the preparation of material for, and volume production by, production printing processes that include offset lithography, letterpress, flexography, gravure, screen and digital printing.

This document does not address spectral measurements appropriate to other specific application needs, such as those used during the production of materials, for example, printing paper and proofing media.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 5-2, Photography and graphic technology — Density measurements — Part 2: Geometric conditions for transmittance density (standards.iteh.ai)

ISO 5-4:2009, Photography and graphic technology — Density measurements — Part 4: Geometric conditions for reflection density https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-

ISO 3664, Graphic technology and photography sist-Viewing-conditions

ISO 11664-1, Colorimetry — Part 1: CIE standard colorimetric observers

ISO 11664-3, Colorimetry — Part 3: CIE tristimulus values

ISO 11664-4, Colorimetry — Part 4: CIE 1976 L*a*b* Colour space

ISO 28178, Graphic technology — Exchange format for colour and process control data using XML or ASCII text

CIE Publication 15:2004, Colorimetry, 3rd ed.

CIE Publication 167:2005, Recommended practice for tabulating spectral data for use in colour computations

CIE Publication 176:2006, Geometric Tolerances for Colour Measurements

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <u>http://www.electropedia.org/</u>
- ISO Online browsing platform: available at http://www.iso.org/obp

3.1

adopted white

spectral radiance distribution as seen by an image capture or measurement device and converted to colour signals that are considered to be perfectly achromatic and to have an observer adaptive luminance factor of unity, i.e. colour signals that are considered to correspond to a perfect white diffuser

[SOURCE: ISO 22028-1]

3.2

bandwidth

width of the spectral response function of the instrument, measured between the half-power points often termed full width at half maximum (FWHM)

3.3

calibration

set of operations that establish, under specified conditions, the relationship between values of quantities indicated by a measuring instrument or measuring system, or values represented by a material measure or a reference material, and the corresponding values realized by standards

Note 1 to entry: Contrary to a common usage, calibration is not the process of adjusting a measurement system such that it produces values that are believed to be correct. Calibration permits either the assignment of values of measurands to the indications (creating a reference table) or the decision to reset or adjust the device. Following the resetting or adjusting of the device, a calibration needs to be verified to ensure that the new device setting(s) provide indications within the accepted values.

[SOURCE: ISO/IEC Guide 99 (VIM)] h STANDARD PREVIEW

3.4

CIE illuminant

(standards.iteh.ai)

illuminant (3.6) defined by the International Commission on Illumination (CIE) in terms of relative spectral power distribution SIST ISO 13655:2018

 SIST ISO 13655:2018

 https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-[SOURCE: IEC 60050-845-03-12]

 21183c0cb3d8/sist-iso-13655-2018

EXAMPLE CIE illuminants A, C, and various D illuminants.

3.5

CIELAB chromaticness difference

$\Delta C_{\rm h}$

difference between two colours of approximately the same lightness projected onto a constant lightness plane in the CIELAB colour space

Note 1 to entry: This is calculated as
$$\Delta C_{h} = \sqrt{\left(\text{CIE}\,\alpha_{1}^{*} - \text{CIE}\,\alpha_{2}^{*}\right)^{2} + \left(\text{CIE}\,b_{1}^{*} - \text{CIE}\,b_{2}^{*}\right)^{2}}$$

3.6

illuminant

numeric tabulation of the relative spectral distribution of the radiant (light) flux incident on the specimen surface

Note 1 to entry: The CIE defines an illuminant as "radiation with a relative spectral power distribution defined over the wavelength range that influences object colour perception". In everyday English, the term is more widely used to mean any kind of light falling on a body or scene. See IEC 60050-845 for further information.

[SOURCE: IEC 60050-845-03-10]

3.7

opacity

<of a substrate> measure of the property that describes the ability of a specimen to hide a surface behind and in contact with it

Note 1 to entry: The numerical value of opacity as used in this document is 100 times the ratio of the luminous reflectance factor of the substrate over black backing (as defined in $\underline{A.2}$) to the luminous reflectance factor over white backing (as defined in $\underline{A.3}$). This is different from the measurement of opacity used by the paper manufacturing industry and defined in ISO 2471.

3.8

opaque substrate

substrate whose *opacity* (3.7), measured according to A.3, is 0,99 or greater

3.9

transparent substrate

clear material having minimal absorption or scattering of transmitted visible light

Note 1 to entry: Clear packaging film is an example of this type of material.

3.10

3.11

reflectance factor

ratio of the radiant or luminous flux reflected in the directions delimited by the given cone to that reflected in the same directions by a perfect reflecting diffuser identically irradiated or illuminated

Note 1 to entry: The industry commonly uses the term reflectance rather than reflectance factor.

Note 2 to entry: It is important to specify the geometry that establishes the given conditions of measurement. See <u>Annex B</u>. (standards.iteh.ai)

[SOURCE: IEC 60050-845-04-64]

SIST ISO 13655:2018

21183c0cb3d8/sist-iso-13655-2018

https://standards.iteh.ai/catalog/standards/sist/486c71a1-432c-4d0e-b9fa-

radiance factor

<at a surface element of a non-self-radiating medium, in a given direction, under specified conditions of irradiation> ratio of the radiance of the surface element in the given direction to that of the perfect reflecting or transmitting diffuser identically irradiated and viewed

Note 1 to entry: For photoluminescent (fluorescent) media, the radiance factor contains 2 components, the reflected radiance factor, β_R , and the luminescent radiance factor, β_L . The sum of the reflected and luminescent radiance factors is the total radiance factor, β_T : $\beta_T = \beta_R + \beta_L$. The subscript R is used here for the reflected radiance factor because it is more intuitive than the traditional S and avoids confusion with the use of S to denote a state of polarization.

[SOURCE: IEC 60050-845-04-68]

3.12

specimen backing

material placed behind and in contact with the specimen during measurement

Note 1 to entry: For this document, this can be either white or black.

3.13

spectrophotometer

instrument for measuring the relative spectral *reflectance factor* (3.10) or *transmittance factor* (3.18) of a material across the visible spectrum in order to derive colorimetric quantities

3.14

spectroradiometer

instrument for measuring radiometric quantities in narrow wavelength intervals over a given spectral region

[SOURCE: IEC 60050-845-05-07]

3.15

standardization

process of forcing or adjusting a measurement system to produce readings that correspond to a previously established *calibration* (3.3) using one or more homogeneous specimens or certified reference materials

Note 1 to entry: As defined here, standardization is normally carried out by an instrument user.

3.16

telespectroradiometer

spectroradiometer (3.14) that uses an optical relay component to allow measurements to be made at a distance from the specimen

3.17

transmittance (for incident radiation of a given spectral composition, polarization, and geometrical distribution)

ratio of the transmitted radiant or luminous flux to the incident flux in the given conditions

Note 1 to entry: It is important to specify the geometry that establishes the given conditions of measurement, for example, rectilinear geometry produces regular transmittance and integrating sphere produces diffuse transmittance. But an opal glass diffuser does not produce the same readings as an integrating sphere geometry. See <u>Annex B</u>.

[SOURCE: IEC 60050-845-04-59]

3.18

transmittance factor iTeh STANDARD PREVIEW

ratio of flux transmitted by a specimen in a given optical system to the flux transmitted when the specimen is removed from the sampling aperture

Note 1 to entry: For example, this is the case when radiation penetrating a slide situated in a projector and reaching a screen is compared to the radiation, when the slide is removed from a projector and only an empty slide mount is in the projector. 21183c0cb3d8/sist-iso-13655-2018

4 Spectral measurement requirements

4.1 Instrument standardization and adjustment

The measurement device or system shall be verified (standardized and possibly adjusted) in accordance with its manufacturer's instructions. See also <u>Annexes C</u> and <u>D</u>.

NOTE 1 ISO 15790 defines the use of a certified reference material (CRM) to check calibration of a measurement system. It also provides additional information relating to the use of CRMs, the determination of combined standard uncertainty and data reporting.

NOTE 2 Where multiple instruments are used for measurement, there can be differences in the resulting data due to the individual characteristics of the instruments and variations in measurement conditions. <u>Annexes C</u> and <u>D</u> provide information on the improvement of inter-instrument agreement and the use of certified reference materials.

4.2 Reflectance factor measurement

4.2.1 Wavelength range, wavelength interval and bandwidth

The data should be measured from 380 nm to 780 nm and shall be measured from 400 nm to 700 nm, inclusive. Data should be measured at 5 nm intervals with a spectral response function that is triangular with a 5 nm bandwidth at the half-power point, as specified in ISO 11664-3. Where unknown data are measured at other intervals and bandwidths, the sampling interval and bandwidth shall not exceed 10 nm. For applications where the spectral properties of the specimens are well established, conformance to process requirements may be assessed using 20 nm sampling. Measurement data taken

at greater than 10 nm interval shall be converted to 10 nm using one of the interpolation methods recommended in CIE Publication 167:2005. Where measurement data are collected at bandwidths and intervals of less than 5 nm, it may be widened using the method of <u>Annex E</u>.

4.2.2 Illumination requirements and measurement conditions

4.2.2.1 Measurement condition M0

Historically, many spectrophotometers used in the graphic arts have used an incandescent lamp with a relative spectral power distribution that is close to CIE standard illuminant A, as defined in ISO 11664-2. In addition, this illuminant has historically been required for the measuring of density. M0 is provided to allow the identification of data measured using existing instrumentation or instrumentation optimized for photographic density measurements (see ISO 5-3).

The relative spectral power distribution of the flux incident on the specimen surface should conform to CIE illuminant A (corresponding to an incandescent source with a correlated colour temperature of 2 856 K). In practical instruments, this may be achieved using any source that provides radiant power at all wavelengths within the spectral range of 400 nm to 700 nm.

Because the specification of correlated colour temperature does not define UV, the UV content is not controlled under M0, and it is therefore recommended that M1 be used when there is the need to interchange data measured on samples that exhibit fluorescence. When instruments meeting M1 are not available and relative data are sufficient for process control or other data exchange applications, M0 instruments of like manufacturer and model provide a viable alternative.

iTeh STANDARD PREVIEW

4.2.2.2 Measurement condition M1 (standards.iteh.ai)

To minimize the variations in measurement results between instruments due to fluorescence (by optical brighteners in the substrate and/or fluorescence of the printing and/or proofing colorants), the spectral power distribution of the light flux incident on the specimen surface for the measurement should match CIE illuminant D50._{21183c0cb3d8/sist-iso-13655-2018}

NOTE 1 Because ISO 3664 also specifies the use of D50, this will improve the consistency between measurement results made under condition M1 and visual assessment in viewing booths that meet the requirements of ISO 3664.

NOTE 2 For material testing as defined in ISO 5631-3, the UV-content of the illumination on the test piece has been adjusted to conform to that of CIE illuminant C. Therefore, measurements conforming to ISO 5631-3 might not be compatible with measurements conforming to this document.

There are two methods to achieve conformance to condition M1.

- a) The spectral power distribution of the measurement source at the sample plane should match CIE illuminant D50. It shall conform to the requirements for viewing condition P1 of ISO 3664. This method shall be used when both luminescent colorants and optical brighteners are of concern. The instrument manufacturer shall supply a representative spectral power distribution of the measurement source at the sample plane with the instrument documentation.
- b) A spectral match of the spectral power distribution of the measurement source in the range from 400 nm to 700 nm at the sample plane is not required if a compensation method is used with a controlled adjustment of the radiant power in the UV spectral region below 400 nm^{[24][25]}. This can be done by active adjustment of the relative power in this range with respect to a calibrated standard for D50. This compensation aims only to correct the effects of fluorescence of optical brighteners in the substrate. The spectral power distribution in the range from 400 nm to 700 nm shall contain radiant power at all wavelengths in this range.

It should be noted that for the proper evaluation of materials with optical brightening agents, it is important that the ratio of the power in the region between 300 nm and 400 nm to the power in the region between 400 nm to 500 nm be very similar to the ratio of D50 between these same regions.